

United States Patent [51] Patent Number: 5,818,749

Hartfield [45] Date of Patent: Oct. 6, 1998

[54] INTEGRATED CIRCUIT MEMORY DEVICE

[52] Inventor: Steven T. Hartfield, Everett, MI

[73] Assignee: Micron Technology, Inc., Boise, ID

[11] Appl. No.: 894,844

[22] Filed: Feb. 24, 1997

Related U.S. Application Data

[63] Continuation-in-part of Ser. No. 348,647, Dec. 1, 1994, Pat. No. 5,646,879, which is a continuation of Ser. No. 110,204, Aug. 10, 1991, Pat. No. 5,379,250.

[51] Int. Cl. 1 GLC 17/06

[52] U.S. Cl. 365/103, 365/104, 365/175, 365/225.7, 257/510, 250

[58] Field of Search 365/103, 365/104, 365/175, 365/225.7, 257/510, 250

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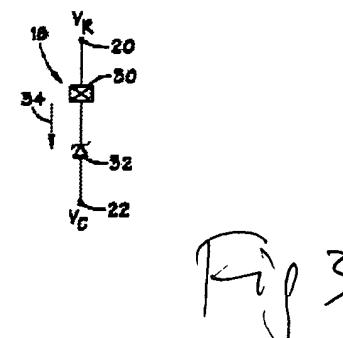
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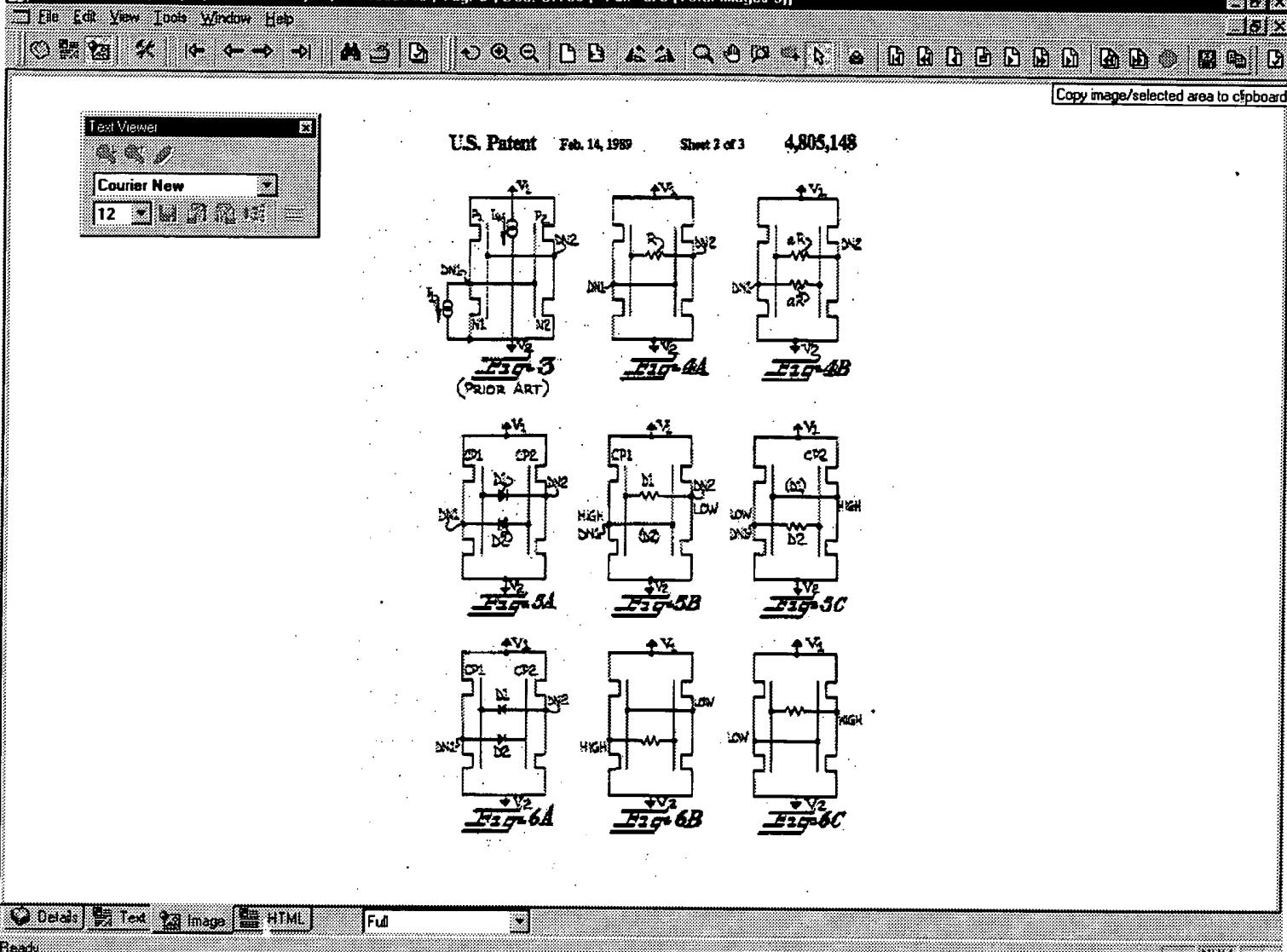
Primary Examiner—Son T. Dinh
Attorney, Agent, or Firm—Kaufner, Yoder & Edwards

[57] ABSTRACT

A memory array using structure changing memory elements in a reverse biased diode array is disclosed. A memory cell is programmed and read by reverse biasing the diode to overcome the diode's breakdown voltage. The disclosed reverse biased diode array exhibits much less substrate current leakage than a similar forward biased diode array.

47 Claims, 3 Drawing Sheets





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61	<input type="checkbox"/>	US 5432740 A	19950711	11	Low voltage flash EEPROM memory cell with merge	365/185.27	257/316; 257/317;	
62	<input type="checkbox"/>	US 5311039 A	19940510	34	PROM and ROM memory cells	257/50	257/530; 257/73;	
63	<input type="checkbox"/>	US 5091881 A	19920225	15	Multiple port memory including merged bipolar	365/155	365/156; 365/225.6;	
64	<input type="checkbox"/>	US 5086414 A	19920204	48	Semiconductor device having latch means	365/230.08	365/233	
65	<input type="checkbox"/>	US 5029129 A	19910702	9	High-speed bipolar memory system	365/155	365/179	
66	<input type="checkbox"/>	US 4845679 A	19890704	14	Diode-FET logic circuitry	365/189.02	326/118; 326/44;	
67	<input type="checkbox"/>	US 4805148 A	19890214	9	High impedance-coupled CMOS SRAM for improved single	365/154	257/297; 257/904;	
68	<input type="checkbox"/>	US 4799192 A	19890117	5	Three-transistor content addressable memory	365/49	365/181	
69	<input type="checkbox"/>	US 4701883 A	19871020	5	ECL/CMOS memory cell with separate read and write bit	365/154	365/156; 365/175	
70	<input type="checkbox"/>	US 4488261 A	19841211	13	Field programmable device	365/104	365/105	
71	<input type="checkbox"/>	US 4460984 A	19840717	12	Memory array with switchable upper and lower word lines	365/190	365/154	

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5	<input type="checkbox"/>	US 20030031067 A1	20030213	32	Method for making a three-dimensional memory	365/200		
6	<input type="checkbox"/>	US 20030027378 A1	20030206	31	Method for programming a threedimensional memory	438/131		
7	<input type="checkbox"/>	US 20030026121 A1	20030206	39	Vertically stacked field programmable nonvolatile	365/130		
8	<input type="checkbox"/>	US 20030022420 A1	20030130	32	Three-dimensional memory array incorporating serial	438/131		
9	<input type="checkbox"/>	US 20030016553 A1	20030123	39	Vertically stacked field programmable nonvolatile	365/103		
10	<input type="checkbox"/>	US 20030003632 A1	20030102	26	Formation of antifuse structure in a three	438/131	257/530; 438/600	
11	<input type="checkbox"/>	US 20020163035 A1	20021107	15	CURRENT SOURCE COMPONENT WITH PROCESS TRACKING	365/185.18		

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12			US 20020141233	20021003	30	semiconductor memory device including memory cell	365/158		
	A1								
13			US 20020140051	20021003	19	Three-dimensional memory array and method of	257/530		
	A1								
14			US 20020110021	20020815	21	Non-volatile semiconductor memory device having	365/185.21		
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15			US 20020106838	20020808	26	Formation of antifuse structure in a three	438/131	257/209;	
	A1						438/128		
16			US 20020088998	20020711	19	THREE-DIMENSIONAL MEMORY ARRAY AND METHOD OF	257/202		
	A1								
17			US 20020081851	20020627	21	METHOD OF FORMING NONVOLATILE MEMORY DEVICE	438/690		
	A1								
18			US 20020081782	20020627	23	Contact and via structure and method of fabrication	438/131	438/637;	
	A1						438/640		
19			US 20020081753	20020627	12	Formation of arrays of microelectronic elements	438/3		
	A1								
20			US 20020079553	20020627	22	Contact and via structure and method of fabrication	257/530	257/774;	
	A1						257/775;		
21			US 20020075719	20020620	14	Low-cost three-dimensional memory array	365/130		
	A1								
22			US 20020050606	20020502	57	SEMI-MONOLITHIC MEMORY WITH HIGH-DENSITY CELL	257/202	257/E27.075	
	A1								

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24	<input type="checkbox"/>	US 20020027793	20020307	41	Vertically stacked field programmable nonvolatile	365/103	257/E27.073	
25	<input type="checkbox"/>	US 20020018355	20020214	41	Vertically stacked field programmable nonvolatile	365/103	257/E27.073	
26	<input type="checkbox"/>	US 20010055838	20011227	28	Nonvolatile memory on SOI and compound semiconductor	438/129		
27	<input type="checkbox"/>	US 20010048608	20011206	21	Magnetic random access memory circuit	365/158		
28	<input type="checkbox"/>	US 20010010938	20010802	15	Diode connected to a magnetic tunnel junction and	438/3	438/246; 438/248;	
29	<input type="checkbox"/>	US 6541312 B2	20030401	24	Formation of antifuse structure in a three	438/131	365/159; 365/175	
30	<input type="checkbox"/>	US 6534403 B2	20030318	21	Method of making a contact and via structure	438/666	438/625; 438/669;	
31	<input checked="" type="checkbox"/>	US 6515897 B1	20030204	16	Magnetic random access memory using a non-linear	365/173	365/145; 365/171	
32	<input type="checkbox"/>	US 6515888 B2	20030204	14	Low cost three-dimensional memory array	365/130	365/105; 365/113;	
33	<input type="checkbox"/>	US 6504761 B2	20030107	21	Non-volatile semiconductor memory device improved sense	365/185.21	365/189.07; 365/203	

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